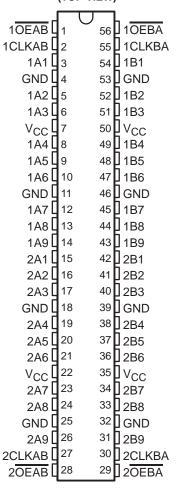
- Members of the Texas Instruments Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines Directly
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V_{CC} and GND Pin Configurations Minimize High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Pin Spacings

description

The 'ACT16474 are noninverting 18-bit registered bus transceivers composed of two 9-bit sections with separate control signals. For either 9-bit transceiver section, data flow in the A-to-B mode is controlled by output-enable (1OEAB or 2OEAB) and clock (1CLKAB or 2CLKAB) inputs. When 1OEAB or 2OEAB is low, the corresponding outputs are active (high or low) and take on either the current data on low-to-high transition of 1CLKAB or 2CLKAB or the previously stored data if 1CLKAB or 2CLKAB is low.

54ACT16474...WD PACKAGE 74ACT16474...DL PACKAGE (TOP VIEW)



When 1 OEAB or 2 OEAB is high, the corresponding outputs are in the high-impedance state. 1 OEAB or 2 OEAB does not affect the operation on the internal registers. Previously stored data can be retained or new data can be entered while the outputs are in the high-impedance state.

Data flow from B to A is similar, but uses 10EBA and/or 20EBA and 1CLKBA and/or 2CLKBA.

The 74ACT16474 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16474 is characterized for operation over the full military temperature range of –55°C to 125°C. The 74ACT16474 is characterized for operation from –40°C to 85°C.



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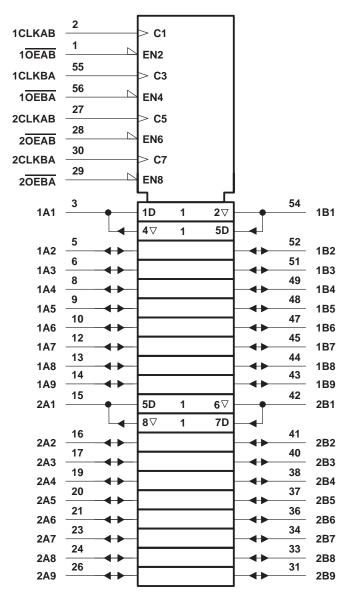


FUNCTION TABLE[†]

ı	OUTPUT		
CLKAB	OEAB	Α	В
Х	Н	Χ	Z
L	L	Χ	В ₀ ‡
1	L	Н	Н
1	L	L	L

[†] A-to-B data flow is shown: B-to-A flow is similar but uses CLKBA, and OEBA.

logic symbol§

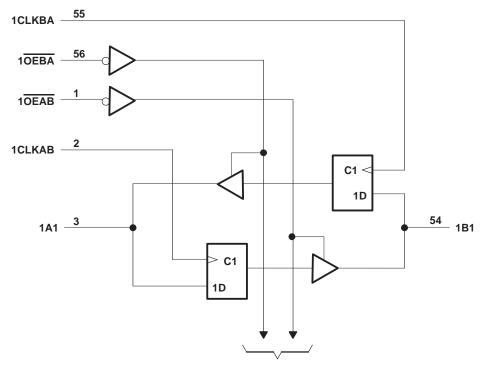


§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

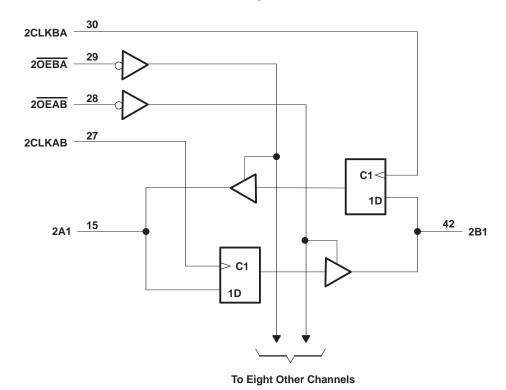


[‡]Output level before the indicated steadystate input conditions were established

logic diagram (positive logic)



To Eight Other Channels





54ACT16474, 74ACT16474 18-BIT REGISTERED BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

SCAS238A - MAY 1992 - REVISED APRIL 1996

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	–0.5 to 7 V
Input voltage range, V _I (see Note 1)	-0.5 to $V_{CC} + 0.5 V$
Input voltage range, V _O (see Note 1)	-0.5 to $V_{CC} + 0.5 V$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±450 mA
Maximum package power dissipation at T _A = 55°C (in still air) (see Note 2): DL package	e 1.4 W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

		54ACT16474			74ACT16474			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		7	2			V
VIL	Low-level input voltage		Š	0.8			0.8	V
٧ _I	Input voltage	0	70	VCC	0		VCC	V
۷o	Output voltage	0	7	VCC	0		VCC	V
loh	High-level output current		3	-24			-24	mA
loL	Low-level output current	20,	57	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	, I	T,	Δ = 25°C		54ACT	16474	74ACT	16474	UNIT	
		TEST CONDITIONS	Vcc	MIN	TYP N	IAX	MIN	MAX	MIN	MAX	UNII	
		Jan - 50 A	4.5 V	4.4			4.4		4.4			
		I _{OH} = -50 μA	5.5 V	5.4			5.4		5.4			
Vон		Jan - 24 mA	4.5 V	3.94			3.8		3.8		V	
		I _{OH} = -24 mA	5.5 V	4.94			4.8		4.8			
		I _{OH} = -75 mA [†]					3.85		3.85			
		I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1		
		IOL = 90 μA	5.5 V			0.1		0.1		0.1		
V _{OL}		le 24 mA	4.5 V		(0.36		0.44		0.44	V	
		I _{OL} = 24 mA	5.5 V		(0.36		0.44		0.44		
		I _{OL} = 75 mA [†]	5.5 V				()	1.65		1.65		
IĮ	Control inputs	V _I = V _{CC} or GND	5.5 V		±	±0.1	200	±1		±1	μΑ	
loz‡	A or B ports	$V_O = V_{CC}$ or GND	5.5 V		±	±0.5	75	±5		±5	μΑ	
Icc		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80		80	μΑ	
ΔI _{CC} §		One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			0.9		1		1	mA	
Ci	Control inputs	V _I = V _{CC} or GND	5 V		3						pF	
C _{io}	A or B ports	$V_O = V_{CC}$ or GND	5 V		11.5						pF	

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

				25°C	54ACT16474		74ACT16474		UNIT	
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
fclock	Clock frequency		0	75	0	75	0	75	MHz	
	Pulse duration	CLK high	4		4	10,7	4			
t _w		CLK low	6.6		6.6	TEN.	6.6		ns	
t _{su}	Setup time	Data before CLK↑	5.5		5.5		5.5		ns	
th	Hold time	Data after CLK↑	1		1		1		ns	

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	T,	4 = 25°C	;	54ACT	16474	74ACT	16474	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f _{max}			75			75	2	75		MHz
^t PLH	CLK	A or B	4	8	10.2	4	11.5	4	11.5	ns
^t PHL	CLK		4.2	8	10.2	4.2	11.4	4.2	11.4	115
^t PZH		A or B	3	7.8	10.3	3	11.7	3	11.7	ns
t _{PZL}	ŌĒ	AOIB	3.7	9.2	11.6	3.7	13.1	3.7	13.1	115
^t PHZ	ŌĒ	A or B	4.8	7.1	8.8	4.8	9.5	4.8	9.5	nc
^t PLZ	OE .	AOIB	4.4	6.6	8.4	4.4	9	4.4	9	ns



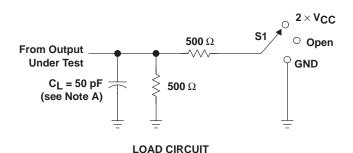
[‡] For I/O ports, the parameter IOZ includes the input leakage current.

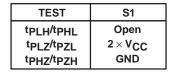
[§] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

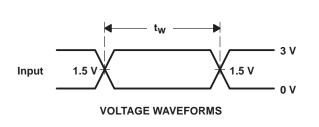
operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

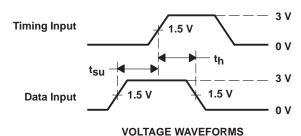
PARAMETER			TEST CON	TYP	UNIT
C _{pd} Power dissipation capacitance per transceiver	Outputs enabled	C. = 50 pE	f = 1 MHz	61	nE.
	Outputs disabled	$C_L = 50 \text{ pF},$	1 = 1 IVIIIZ	37	ρı

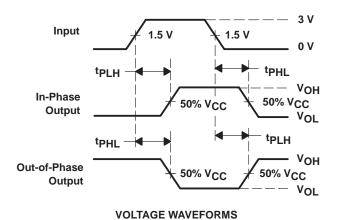
PARAMETER MEASUREMENT INFORMATION

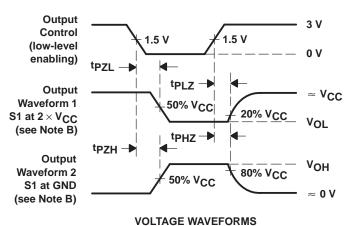












NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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